

# **Features**

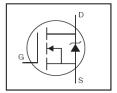
- · Advanced Process Technology
- Ultra Low On-Resistance
- 175°C Operating Temperature
- Fast Switching
- Repetitive Avalanche Allowed up to T<sub>imax</sub>
- Multiple Package Options
- Lead-Free

# Description

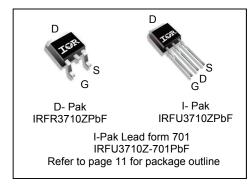
This HEXFET® Power MOSFET utilizes the latest processing techniques to achieve extremely low on-resistance per silicon area. Additional features of this design are a 175°C junction operating temperature, fast switching speed and improved repetitive avalanche rating . These features combine to make this design an extremely efficient and reliable device for use in a wide variety of applications.

# IRFU3710Z-701PbF

HEXFET® Power MOSFET



V <sub>DSS</sub>	100V
$R_{DS(on)}$	18mΩ
I <sub>D</sub>	42A



G	D	S
Gate	Drain	Source

B. J. J.		Standard Pack		Onderselle Bort Namehou	
Base part number	Package Type	Form	Quantity	Orderable Part Number	
IRFU3710ZPbF	I-Pak	Tube	75	IRFU3710ZPbF	
IDEDOZACZDI E	D.D.J.	Tube	75	IRFR3710ZPbF	
IRFR3710ZPbF	D-Pak	Tape and Reel Left	3000	IRFR3710ZTRLPbF	

# **Absolute Maximum Ratings**

Symbol	Parameter	Max.	Units
I <sub>D</sub> @ T <sub>C</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V (Silicon Limited)	56	
I <sub>D</sub> @ T <sub>C</sub> = 100°C	Continuous Drain Current, V <sub>GS</sub> @ 10V	39	Α
I <sub>D</sub> @ T <sub>C</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V (Package Limited)	42	A
I <sub>DM</sub>	Pulsed Drain Current ①	220	
$P_D @ T_C = 25^{\circ}C$	Maximum Power Dissipation	140	W
	Linear Derating Factor	0.95	W/°C
$V_{GS}$	Gate-to-Source Voltage	± 20	V
E <sub>AS (Thermally limited)</sub>	Single Pulse Avalanche Energy®	150	m l
E <sub>AS (Tested)</sub>	Single Pulse Avalanche Energy Tested Value®	200	mJ
I <sub>AR</sub>	Avalanche Current①	See Fig.12a, 12b, 15, 16	Α
E <sub>AR</sub>	Repetitive Avalanche Energy ®		mJ
T <sub>J</sub>	Operating Junction and	-55 to + 175	
T <sub>STG</sub>	Storage Temperature Range		°C
	Soldering Temperature, for 10 seconds (1.6mm from case)	300	

# **Thermal Resistance**

Symbol	Parameter	Тур.	Max.	Units
$R_{ hetaJC}$	Junction-to-Case		1.05	
$R_{ heta JA}$	Junction-to-Ambient ( PCB Mount) ⑦		50	°C/W
$R_{ hetaJA}$	Junction-to-Ambient		110	



# IRFR/U3710ZPbF & IRFU3710Z-701PbF

# Electrical Characteristics @ T<sub>J</sub> = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source Breakdown Voltage	100			V	$V_{GS} = 0V, I_D = 250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient		0.088		V/°C	Reference to 25°C, I <sub>D</sub> = 1mA
R <sub>DS(on)</sub>	Static Drain-to-Source On-Resistance		15	18	mΩ	V <sub>GS</sub> = 10V, I <sub>D</sub> = 33A ③
$V_{GS(th)}$	Gate Threshold Voltage	2.0		4.0	V	$V_{DS} = V_{GS}$ , $I_D = 250\mu A$
gfs	Forward Trans conductance	39			S	$V_{DS} = 25V, I_{D} = 33A$
I <sub>DSS</sub>	Drain-to-Source Leakage Current			20	μA	V <sub>DS</sub> = 100V, V <sub>GS</sub> = 0V
.033	,			250	Jan. 1	$V_{DS} = 100V, V_{GS} = 0V, T_{J} = 125^{\circ}C$
I <sub>GSS</sub>	Gate-to-Source Forward Leakage			200	nA	$V_{GS} = 20V$
	Gate-to-Source Reverse Leakage			-200	11/3	V <sub>GS</sub> = -20V
$Q_g$	Total Gate Charge		69	100		I <sub>D</sub> = 33A
$Q_{gs}$	Gate-to-Source Charge		15		nC	V <sub>DS</sub> = 80V
$Q_gd$	Gate-to-Drain ('Miller') Charge		25			V <sub>GS</sub> = 10V ③
$t_{d(on)}$	Turn-On Delay Time		14			$V_{DD} = 50V$
t <sub>r</sub>	Rise Time		43			I <sub>D</sub> = 33A
$t_{d(off)}$	Turn-Off Delay Time		53		ns	$R_G = 6.8\Omega$
t <sub>f</sub>	Fall Time		42			V <sub>GS</sub> = 10V ③
L <sub>D</sub>	Internal Drain Inductance		4.5			Between lead, 6mm (0.25in.)
L <sub>S</sub>	Internal Source Inductance		7.5		nH	from package and center of die contact
C <sub>iss</sub>	Input Capacitance		2930			$V_{GS} = 0V$
C <sub>oss</sub>	Output Capacitance		290		pF	V <sub>DS</sub> = 25V
C <sub>rss</sub>	Reverse Transfer Capacitance		180			f = 1.0MHz
C <sub>oss</sub>	Output Capacitance		1200			$V_{GS} = 0V, V_{DS} = 1.0V, f = 1.0MHz$
C <sub>oss</sub>	Output Capacitance		180			$V_{GS} = 0V, V_{DS} = 80V, f = 1.0MHz$
C <sub>oss</sub> eff.	Effective Output Capacitance		430			$V_{GS}$ = 0V, $V_{DS}$ = 0V to 80V

# **Source-Drain Ratings and Characteristics**

	Parameter	Min.	Тур.	Max.	Units	Conditions
Is	Continuous Source Current (Body Diode)			56	_	MOSFET symbol showing the
I <sub>SM</sub>	Pulsed Source Current (Body Diode) ①			220		integral reverse p-n junction diode.
$V_{SD}$	Diode Forward Voltage			1.3	V	$T_J = 25^{\circ}C, I_S = 33A, V_{GS} = 0V$ ③
t <sub>rr</sub>	Reverse Recovery Time		35	53	ns	$T_J = 25^{\circ}C$ , $I_F = 33A$ , $V_{DS} = 50V$
$Q_{rr}$	Reverse Recovery Charge		41	62	nC	di/dt = 100A/µs ③
t <sub>on</sub>	Forward Turn-On Time	Intrinsio	turn-or	time is	negligibl	e (turn-on is dominated by L <sub>S</sub> +L <sub>D</sub> )

# Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11).
- $\odot$  starting T<sub>J</sub> = 25°C, L = 0.28mH, R<sub>G</sub> = 25 $\Omega$ , I<sub>AS</sub> = 33A,V<sub>GS</sub> =10V. Part not recommended for use above this value.
- ③ Pulse width  $\leq 1.0$ ms; duty cycle  $\leq 2\%$ .
- $\bullet$  C<sub>oss</sub> eff. is a fixed capacitance that gives the same charging time as C<sub>oss</sub> while V<sub>DS</sub> is rising from 0 to 80% V<sub>DSS</sub>
- © Limited by T<sub>Jmax</sub>, see Fig.12a, 12b, 15, 16 for typical repetitive avalanche performance.
- This value determined from sample failure population. 100% tested to this value in production.
- When mounted on 1" square PCB (FR-4 or G-10 Material). For recommended footprint and soldering techniques refer to application note #AN-994.
- ® Refer to D-Pak package for Part Marking, Tape and Reel information

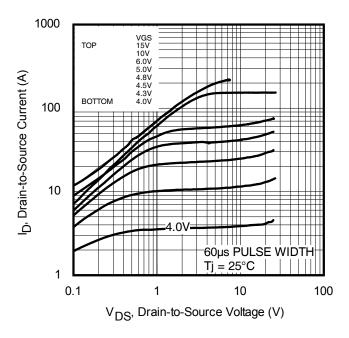


Fig. 1 Typical Output Characteristics

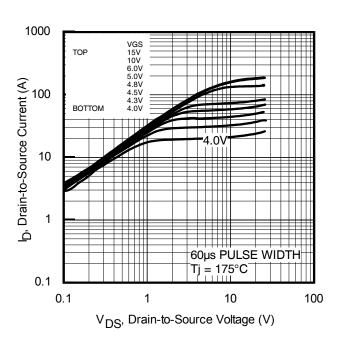


Fig. 2 Typical Output Characteristics

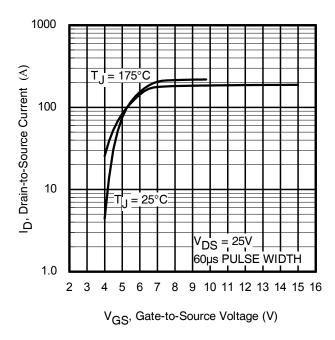
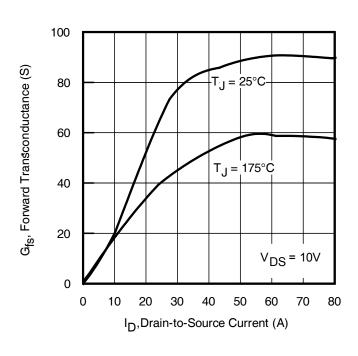
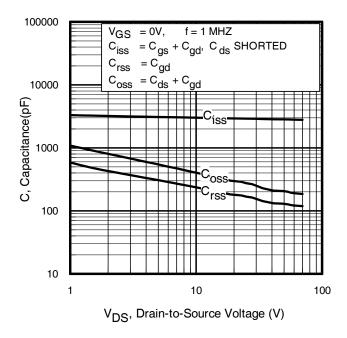


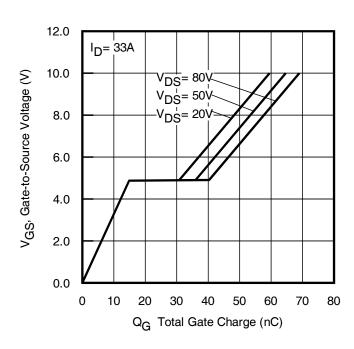
Fig. 3 Typical Transfer Characteristics



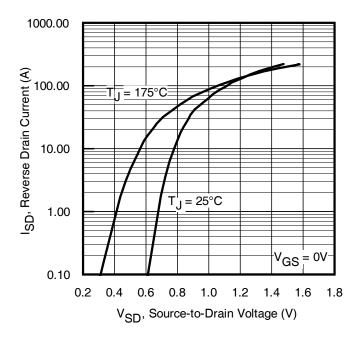
**Fig. 4** Typical Forward Transconductance vs. Drain Current



**Fig 5.** Typical Capacitance vs. Drain-to-Source Voltage



**Fig 6.** Typical Gate Charge vs. Gate-to-Source Voltage



**Fig. 7** Typical Source-to-Drain Diode Forward Voltage

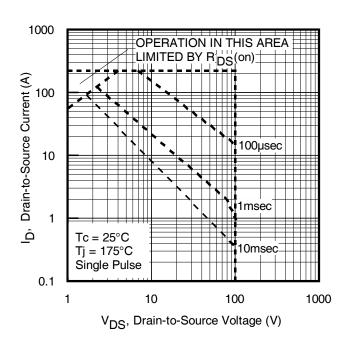
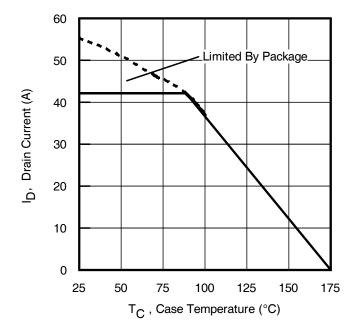


Fig 8. Maximum Safe Operating Area





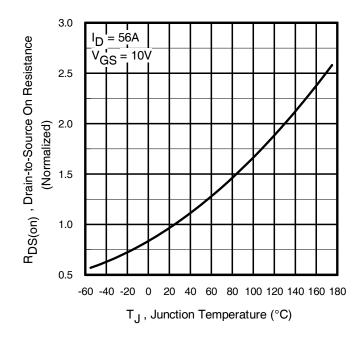


Fig 9. Maximum Drain Current vs. Case Temperature

**Fig 10.** Normalized On-Resistance vs. Temperature

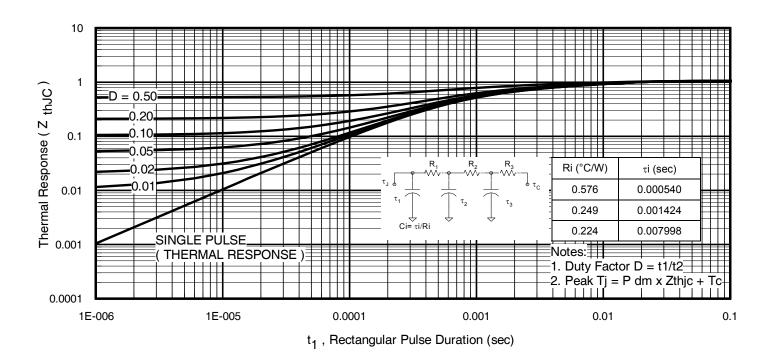


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case



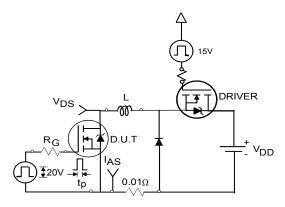


Fig 12a. Unclamped Inductive Test Circuit

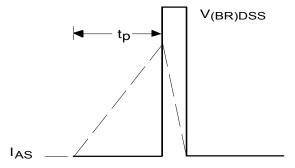


Fig 12b. Unclamped Inductive Waveforms

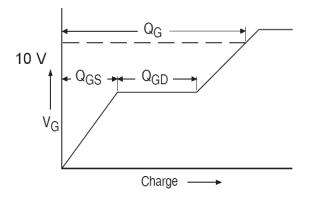


Fig 13a. Gate Charge Waveform

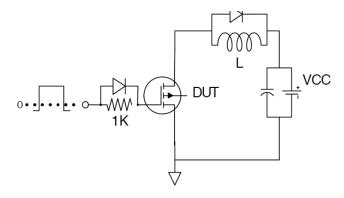
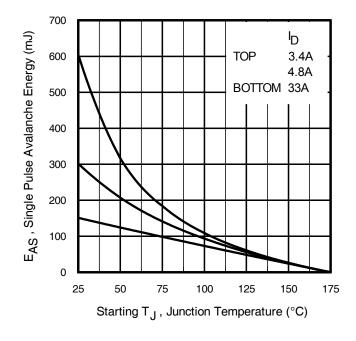


Fig 13b. Gate Charge Test Circuit



**Fig 12c.** Maximum Avalanche Energy vs. Drain Current

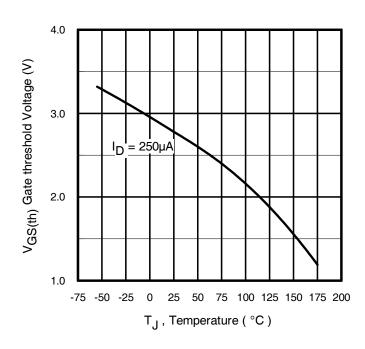


Fig 14. Threshold Voltage vs. Temperature



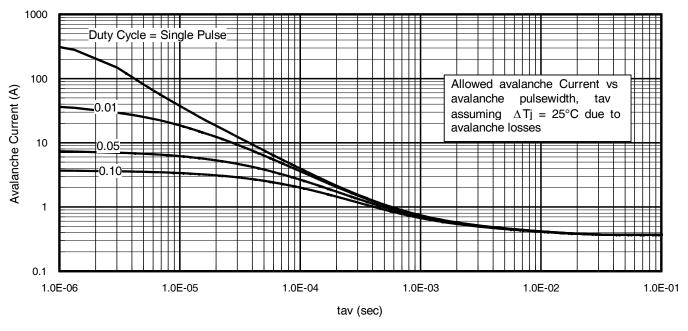
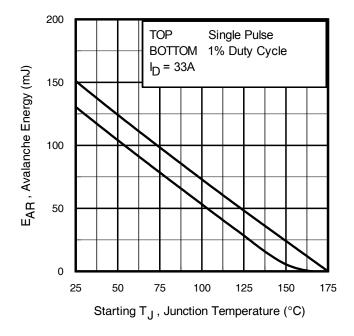


Fig 15. Typical Avalanche Current vs. Pulse width



**Fig 16.** Maximum Avalanche Energy vs. Temperature

# Notes on Repetitive Avalanche Curves , Figures 15, 16: (For further info, see AN-1005 at www.infineon.com)

- Avalanche failures assumption:
   Purely a thermal phenomenon and failure occurs at a temperature far in excess of T<sub>jmax</sub>. This is validated for every part type.
- 2. Safe operation in Avalanche is allowed as long as T<sub>jmax</sub> is not exceeded.
- 3. Equation below based on circuit and waveforms shown in Figures 12a, 12b.
- 4. P<sub>D (ave)</sub> = Average power dissipation per single avalanche pulse.
- 5. BV = Rated breakdown voltage (1.3 factor accounts for voltage increase during avalanche).
- 6. I<sub>av</sub> = Allowable avalanche current.
- 7.  $\Delta T$  = Allowable rise in junction temperature, not to exceed  $T_{jmax}$  (assumed as 25°C in Figure 15, 16).

 $t_{av}$  = Average time in avalanche.

D = Duty cycle in avalanche =  $t_{av} \cdot f$ 

 $Z_{thJC}(D, t_{av})$  = Transient thermal resistance, see figure 11)

$$\begin{split} P_{D \text{ (ave)}} &= 1/2 \text{ ( } 1.3 \cdot \text{BV} \cdot \text{I}_{av} \text{)} = \Delta \text{T} / \text{ Z}_{thJC} \\ I_{av} &= 2\Delta \text{T} / \text{ [} 1.3 \cdot \text{BV} \cdot \text{Zth]} \\ E_{AS \text{ (AR)}} &= P_{D \text{ (ave)}} \cdot t_{av} \end{split}$$



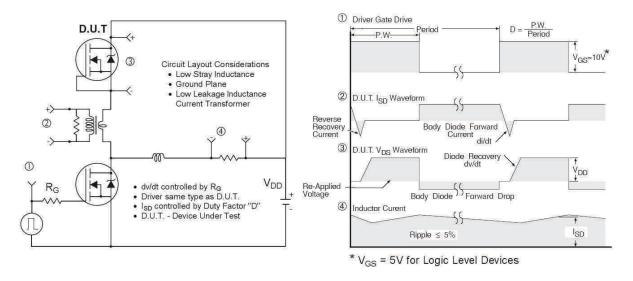


Fig 17. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs

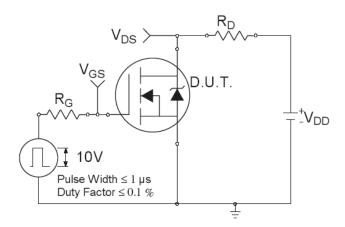


Fig 18a. Switching Time Test Circuit

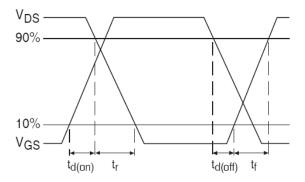
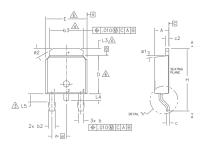


Fig 18b. Switching Time Waveforms

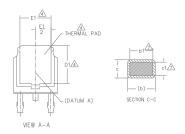


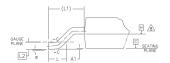
# IRFR/U3710ZPbF & IRFU3710Z-701PbF

# D-Pak (TO-252AA) Package Outline (Dimensions are shown in millimeters (inches))









- 1.- DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994
- 2.- DIMENSION ARE SHOWN IN INCHES [MILLIMETERS].
- A. LEAD DIMENSION UNCONTROLLED IN L5.
- A- DIMENSION D1, E1, L3 & b3 ESTABLISH A MINIMUM MOUNTING SURFACE FOR THERMAL PAD.
- 5.— SECTION C-C DIMENSIONS APPLY TO THE FLAT SECTION OF THE LEAD BETWEEN .005 AND 0.10 [0.13 AND 0.25] FROM THE LEAD TIP.
- DIMENSION D & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED .006 [0.15] PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTMOST EXTREMES OF THE PLASTIC BODY.
- A- DIMENSION 61 & c1 APPLIED TO BASE METAL ONLY.
- A- DATUM A & B TO BE DETERMINED AT DATUM PLANE H.
- 9.- OUTLINE CONFORMS TO JEDEC OUTLINE TO-252AA

S		DIMEN	ISIONS		N O T	
M B	MILLIM	ETERS	INC	INCHES		
0 L	MIN.	MAX.	MIN.	MAX.	E S	
Α	2.18	2.39	.086	.094		
A1	_	0.13	-	.005		
b	0.64	0.89	.025	.035		
ь1	0.64	0.79	.025	.031	7	
b2	0.76	1,14	.030	.045		
b3	4.95	5.46	.195	.215	4	
С	0.46	0.61	.018	.024		
c1	0.41	0.56	.016	.022	7	
c2	0.46	0.89	.018	.035		
D	5.97	6.22	.235	.245	6	
D1	5.21	-	.205	-	4	
Ε	6.35	6.73	.250	.265	6	
E1	4.32	-	.170	-	4	
е	2.29	BSC	.090	BSC		
Н	9.40	10.41	.370	.410		
L	1.40	1.78	.055	.070		
L1	2.74	BSC	.108	REF.		
L2	0.51	BSC	.020	BSC		
L3	0.89	1.27	.035	.050	4	
L4	-	1.02	-	.040		
L5	1.14	1.52	.045	.060	3	
Ø	0,	10°	0,	10°		
ø1	0,	15°	0,	15°		
ø2	25°	35°	25°	35°		

## LEAD ASSIGNMENTS

### HEXFET

- 2.- DRAIN 3.- SOURCE 4.- DRAIN

## IGBT & CoPAK

- 1.- GATE 2.- COLLECTOR
- 3.- EMITTER
- 4.- COLLECTOR

PART NUMBER

DATE CODE

# D-Pak (TO-252AA) Part Marking Information

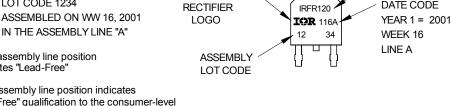
EXAMPLE: THIS IS AN IRFR120 WITH ASSEMBLY

LOT CODE 1234

IN THE ASSEMBLY LINE "A"

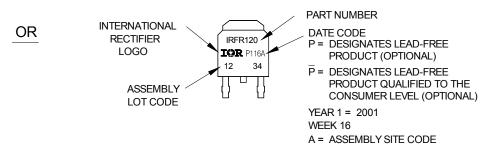
Note: "P" in assembly line position indicates "Lead-Free"

> "P" in assembly line position indicates "Lead-Free" qualification to the consumer-level



IRFR120

INTERNATIONAL



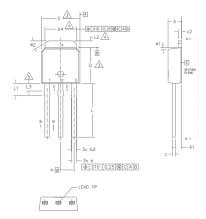
# Notes:

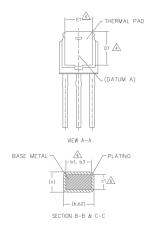
- For an Automotive Qualified version of this part please seehttp://www.infineon.com/product-info/datasheets/data/auirfr3710z.pdf
- For the most current drawing please refer to Infineon website at http://www.infineon.com/package/





# I-Pak (TO-251AA) Package Outline Dimensions are shown in millimeters (inches)





- 1.- DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994
- 2.- DIMENSION ARE SHOWN IN INCHES [MILLIMETERS].
- $\triangle$  dimension D & E do not include mold flash. Mold flash shall not exceed .005 [0.13] Per side. These dimensions are measured at the outmost extremes of the plastic body.
- A- THERMAL PAD CONTOUR OPTION WITHIN DIMENSION 64, L2, E1 & D1.
- A- LEAD DIMENSION UNCONTROLLED IN L3.
- ⚠- DIMENSION 61, 63 & c1 APPLY TO BASE METAL ONLY.
- 7.- OUTLINE CONFORMS TO JEDEC OUTLINE TO-251AA (Date 06/02).
- 8.- CONTROLLING DIMENSION: INCHES.

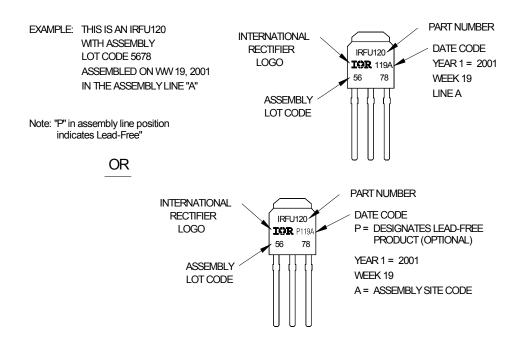
S Y M	DIMENSIONS					
В	MILLIM	ETERS	INC	INCHES		
O L	MIN.	MAX.	MIN.	MAX.	O T E S	
Α	2.18	2.39	.086	.094		
A1	0.89	1.14	.035	.045		
b	0.64	0.89	.025	.035		
ь1	0.65	0.79	.025	.031	6	
b2	0.76	1.14	.030	.045		
ь3	0.76	1.04	.030	.041	6	
b4	4.95	5.46	.195	.215	4	
С	0.46	0.61	.018	.024		
c1	0.41	0.56	.016	.022	6	
c2	0.46	0.89	.018	.035		
D	5.97	6.22	.235	.245	3	
D1	5.21	-	.205	-	4	
Ε	6.35	6.73	.250	.265	3	
E1	4.32	-	.170	-	4	
е	2.29	BSC	.090	BSC		
L	8.89	9.65	.350	.380		
L1	1.91	2.29	.045	.090		
L2	0.89	1.27	.035	.050	4	
L3	0.89	1.52	.035	.060	5	
ø1	0*	15*	0*	15*		
ø2	25°	35°	25*	35*		

### LEAD ASSIGNMENTS

## **HEXFET**

- 1.- GATE
- 2.- DRAIN
- 3.- SOURCE 4.- DRAIN

# I-Pak (TO-251AA) Part Marking Information

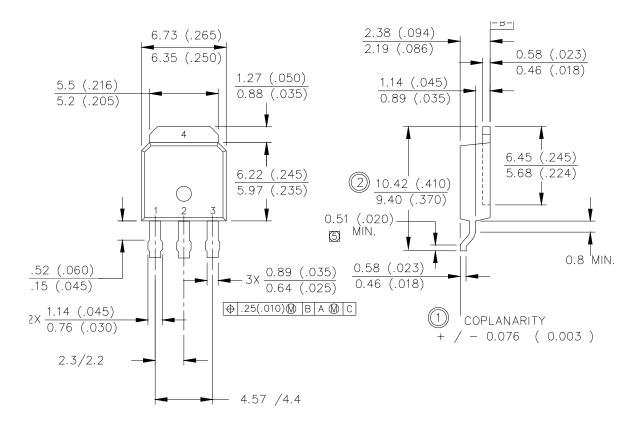


- 1. For an Automotive Qualified version of this part please see<a href="http://www.infineon.com/product-info/auto/">http://www.infineon.com/product-info/auto/</a>
  2. For the most current drawing please refer to Infineon website at <a href="http://www.infineon.com/package/">http://www.infineon.com/package/</a>



# I-Pak Leadform Option 701 Package Outline ®

Dimensions are shown in millimeters (inches)



1-. GATE

2-. DRAIN

3-. SOURCE

4-. DRAIN

# NOTES:

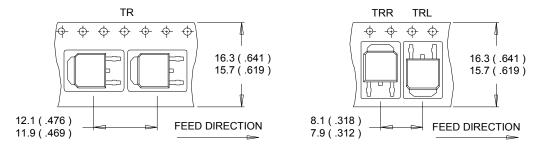
1.0 CONTROL DIMENSIONS IN INCHES

2.0 PARALLELISM AND ANGULARITY MAX. 0.076 (0.003)

3.0 LEADFORM CRITICAL DIMENSIONS DOUBLE RINGED

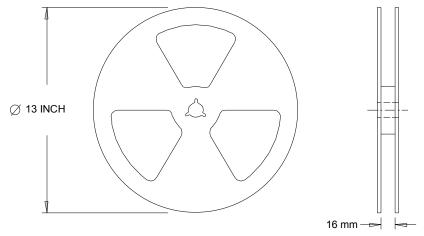


# D-Pak (TO-252AA) Tape & Reel Information Dimensions are shown in millimeters (inches)



# NOTES:

- 1. CONTROLLING DIMENSION: MILLIMETER.
- 2. ALL DIMENSIONS ARE SHOWN IN MILLIMETERS (INCHES).
- 3. OUTLINE CONFORMS TO EIA-481 & EIA-541.



# NOTES:

1. OUTLINE CONFORMS TO EIA-481.

Note: For the most current drawing please refer to Infineon's web site www.infineon.com



# IRFR/U3710ZPbF & IRFU3710Z-701PbF

# Qualification Information<sup>†</sup>

Qualification Level	Industrial (per JEDEC JESD47F) ††				
Moisture Sensitivity Level	D-Pak	MSL1			
Moisture Sensitivity Level	I-Pak	(per JEDEC J-STD-020D) <sup>††</sup>			
RoHS Compliant	Yes				

- † Qualification standards can be found at Infineon's web site www.infineon.com
- †† Applicable version of JEDEC standard at the time of product release.

# **Revision History**

Date	Comments		
5/31/2016	Updated datasheet with corporate template.		
Added disclaimer on last page.			

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